AWG trigger issue with SOC_TML

Issue description

During debugging digital capture test with SOC_TML, it is observed that the AWG trigger is enabled only for the first run, there will be no trigger enabled for the subsequent execution. The original flow has no analog set loaded as it will be generated during test execution. Adding a dummy analog set will help to fix the issue.

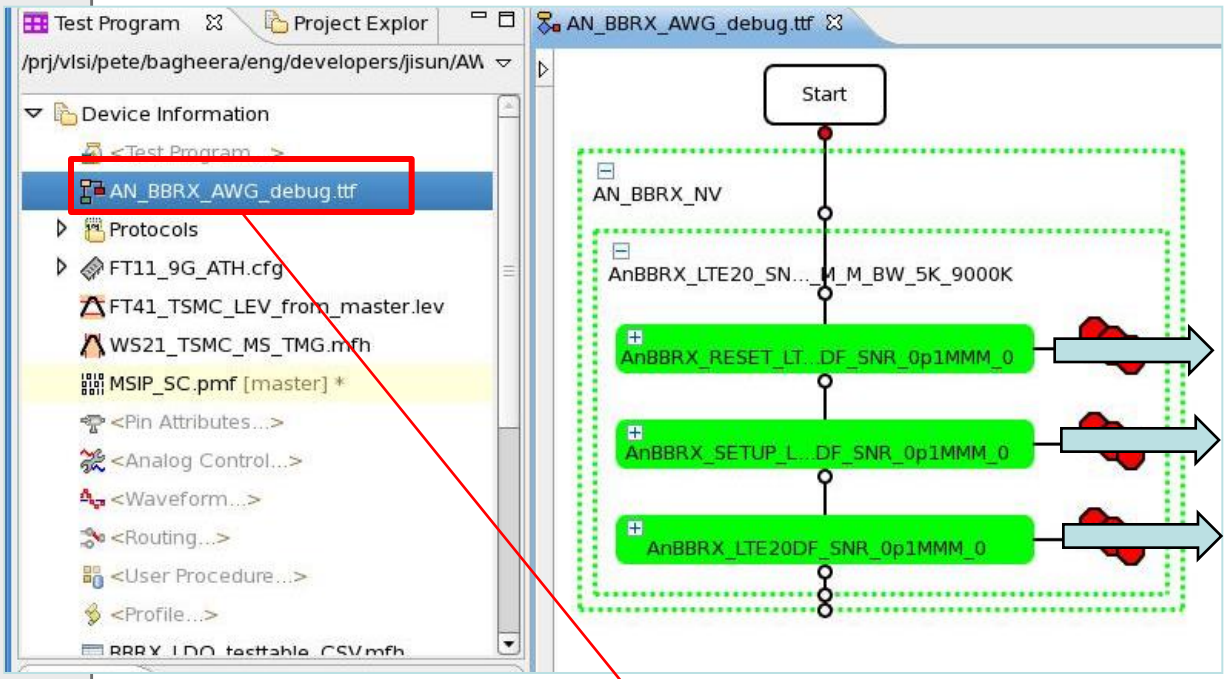
Is this behavior expected? If so, please help to document somewhere that an analog set (even dummy) is needed for mixed signal test.

If not, it think this case is a bug.

Please refer to following slides to reproduce the issue.

To produce. Step 1

i. Download program “AWG_debug.tar.gz” from ftp.verigy.com under folder liyuan
ii. Untar program and load testflow “AN_BBRX_AWG_debug.ttf ” and all setups on R&D high pin count tester **online** under SMT7.2.1.3 with license [PS9G_on_ATH_PS1600_Site1.license]



PA reset

Trigger and generate analog set

Digital capture

Load testflow AN_BBRX_AWG_debug.ttf and all set up (no analog set)

To produce. Step 2

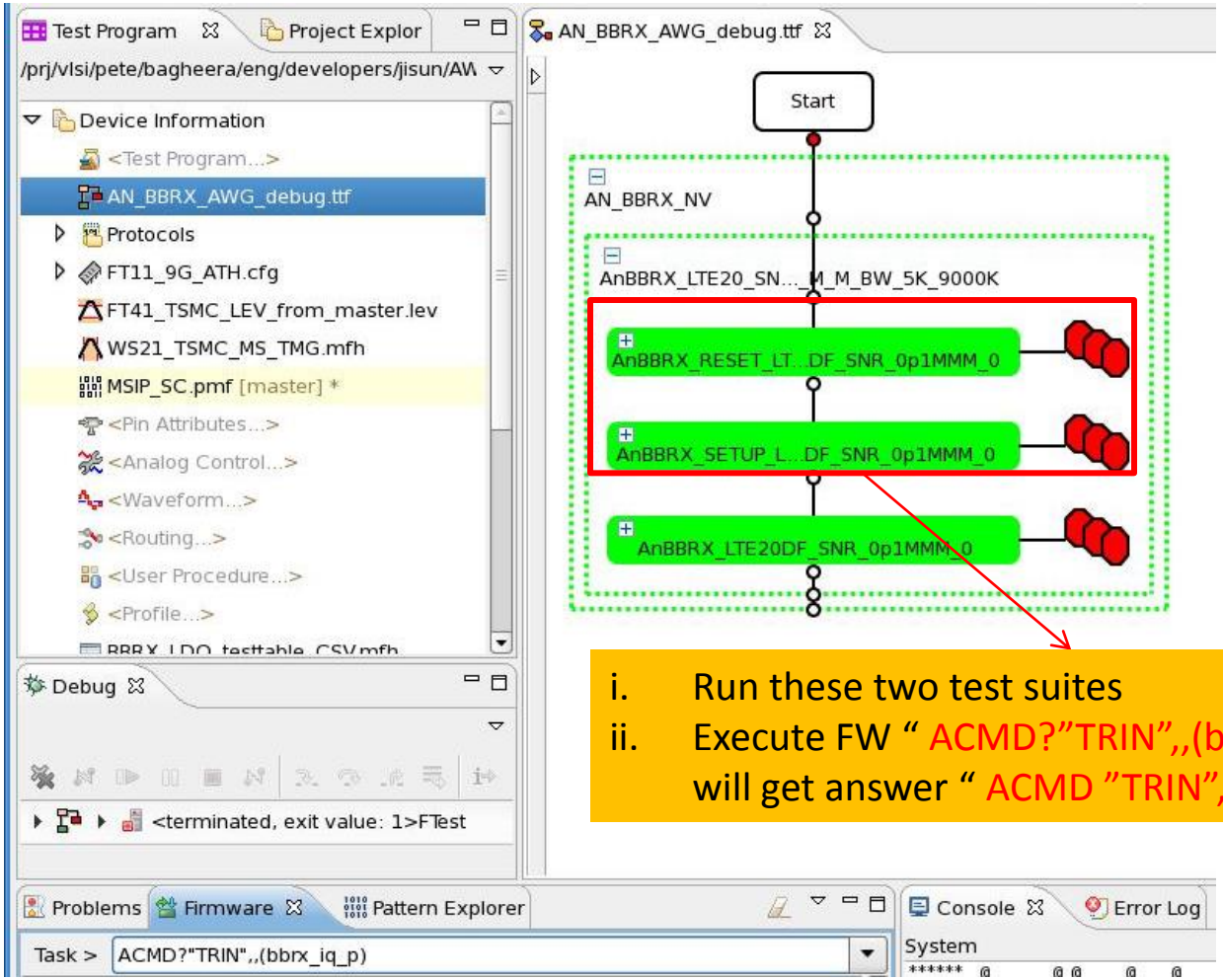
ADVANTEST

i. To use jumper wire to connect digital pin a241 (11615) to MCE23117-S2(CT1) which is to set up trigger connection (could use normal diagnostic board for wire connection)

To produce. Step 3

i. Run the first two test suites together

ii. Execute FW " ACMD?"TRIN",,(bbrx_iq_p) " and will get answer " ACMD "TRIN",YES,(bbrx_iq_p) "

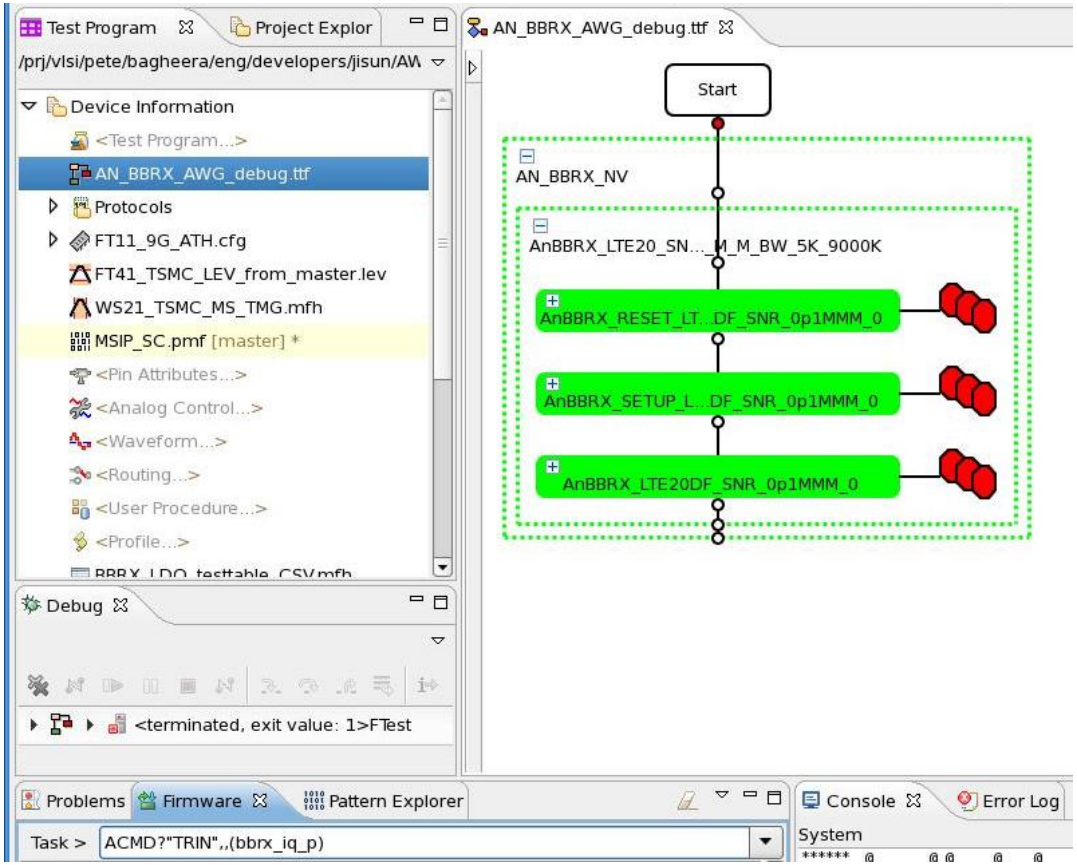


i. Run these two test suites

ii. Execute FW " ACMD?"TRIN",,(bbrx_iq_p) " and will get answer " ACMD "TRIN",YES,(bbrx_iq_p) "

To produce. Step 4

i. Execute the all three test suites together
ii. Then execute the first two test suites together
iii. Execute FW " ACMD?"TRIN",,(bbrx_iq_p) " and will get answer " ACMD "TRIN",**NO**,(bbrx_iq_p) " (No more trigger)
iv. Reload pin configuration and everything could be reproduce again.



To produce. Step 5

i. Create a dummy analog set and run those test suites according to step4 & 5
ii. The trigger will always be enabled.